

## NPTEL Video Lecture Topic List - Created by LinuXpert Systems, Chennai

NPTEL Video Course - Electronics and Communication Engineering - NOC:Digital VLSI Testing

Subject Co-ordinator - Prof. Santanu Chattopadhyay

Co-ordinating Institute - IIT - Kharagpur

Sub-Titles - Available / Unavailable | MP3 Audio Lectures - Available / Unavailable

Lecture 1 - Introduction  
Lecture 2 - Introduction (Continued...)  
Lecture 3 - Introduction (Continued...)  
Lecture 4 - Introduction (Continued...)  
Lecture 5 - DFT  
Lecture 6 - DFT (Continued...)  
Lecture 7 - DFT (Continued...)  
Lecture 8 - DFT (Continued...)  
Lecture 9 - DFT (Continued...)  
Lecture 10 - DFT (Continued...)  
Lecture 11 - Logic and Fault Simulation  
Lecture 12 - Logic and Fault Simulation (Continued...)  
Lecture 13 - Logic and Fault Simulation (Continued...)  
Lecture 14 - Logic and Fault Simulation (Continued...)  
Lecture 15 - Logic and Fault Simulation (Continued...)  
Lecture 16 - Logic and Fault Simulation (Continued...)  
Lecture 17 - Test Generation  
Lecture 18 - Test Generation (Continued...)  
Lecture 19 - Test Generation (Continued...)  
Lecture 20 - Test Generation (Continued...)  
Lecture 21 - Test Generation (Continued...)  
Lecture 22 - Test Generation (Continued...)  
Lecture 23 - Test Generation (Continued...)  
Lecture 24 - Logic BIST  
Lecture 25 - Logic BIST (Continued...)  
Lecture 26 - Logic BIST (Continued...)  
Lecture 27 - Logic BIST (Continued...)  
Lecture 28 - Test Compression  
Lecture 29 - Test Compression (Continued...)

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- Lecture 30 - Test Compression (Continued...)
- Lecture 31 - Test Compression (Continued...)
- Lecture 32 - Low Power Testing
- Lecture 33 - Low Power Testing (Continued...)
- Lecture 34 - Low Power Testing (Continued...)
- Lecture 35 - Low Power Testing (Continued...)
- Lecture 36 - Low Power Testing (Continued...)
- Lecture 37 - Thermal Aware Testing
- Lecture 38 - Thermal Aware Testing (Continued...)
- Lecture 39 - Thermal Aware Testing (Continued...)
- Lecture 40 - Boundary Scan
- Lecture 41 - Boundary Scan (Continued...)
- Lecture 42 - Boundary Scan (Continued...)
- Lecture 43 - Boundary Scan (Continued...)
- Lecture 44 - Boundary Scan (Continued...)
- Lecture 45 - System/Network - On - Chip Test
- Lecture 46 - System/Network - On - Chip Test (Continued...)
- Lecture 47 - System/Network - On - Chip Test (Continued...)
- Lecture 48 - System/Network - On - Chip Test (Continued...)
- Lecture 49 - System/Network - On - Chip Test (Continued...)
- Lecture 50 - System/Network - On - Chip Test (Continued...)
- Lecture 51 - System/Network - On - Chip Test (Continued...)
- Lecture 52 - System/Network - On - Chip Test (Continued...)
- Lecture 53 - System/Network - On - Chip Test (Continued...)
- Lecture 54 - System/Network - On - Chip Test (Continued...)
- Lecture 55 - System/Network - On - Chip Test (Continued...)
- Lecture 56 - System/Network - On - Chip Test (Continued...)
- Lecture 57 - Memory Testing
- Lecture 58 - Memory Testing (Continued...)
- Lecture 59 - Memory Testing (Continued...)
- Lecture 60 - Memory Testing (Continued...)